

ci220 - High Speed Contact Test System



- ICC and IFM testing
- Fully integrated
- Multi standard
- Small form factor
- Easy to use
- Arbitrary waveform generator

ci220 – High Speed Contact Test System

Fully integrated Protocol & Electrical Contact Test System

General Description

The ci220 is the next generation fully integrated contact test system that combines state-of-the-art FPGA and measurement technologies to enable fast, precise and reliable contact testing, development and debugging.



Benefits

- ▣ Time and cost saving
- ▣ All in one test and debug system
- ▣ Fast report generation
- ▣ Easy customer test bench integration
- ▣ Arbitrary waveform generator
- ▣ Integrated real-time scope

Supported Standards / Applications

- ▣ EMV Contact L1
- ▣ ISO 7816
- ▣ GPC SPI/I2C

- ▣ EMV Payment
- ▣ SIM & eSIM
- ▣ Smart Cards
- ▣ Certification testing
- ▣ Development / Debugging

Key Features

- ▣ Supports up to D = 64
- ▣ Low capacitance test slot
- ▣ True analog processing
- ▣ Analog recording for protocol tests
- ▣ Fast custom test case development
- ▣ Flexible API (RCI)
- ▣ Fast LAN / USB3 interface



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